Environmental TEM: Principle, Limitation and Application

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A Look Inside the Reactor



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What is In Situ Microscopy

- Depends on who you ask!
- Observations of materials' dynamic response to an externally applied stimulus in the microscope



Does the light stay on...



Why do We Want to do In Situ Microscopy?

- Conventional electron microscopy does not always tell the full story
 - Samples are (usually) not in their operational environment
- Materials respond dynamically to changes in environment
 - Surface reconstruction due to gas adsorption
 - Phase transitions
 - Growth

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 Essential for establishing structure-activity correlations



 b_5 sites on the (105) surface of Ru. These sites were proposed to be the active sites for N₂ splitting (van Hardeveld and von Montfoort Surf. Sci 4 (1966) 396. Figure adapted from T. W. Hansen *et al.* Catal. Lett. 84 (2002) 7.

In Situ Techniques





Evolution of activity of industrial HDS catalysts, B.M. Moyse, World Refining Jan/Feb (2001) 28 H. Topsøe, J. Catal. 216, 155 (2003)

- In situ XRD
 - Phase determination
 - Good for large areas
- In situ EXAFS, FTIR
 - Coordination
 - Chemical bonding
- Average values
 - No local information
- *In situ* TEM
 - -Gives local information

• Etc...

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Historical Overview of ETEM

- Ambient temperature gas stages
 - E. Ruska: Kolloid. Zeit. 100, 212 (1942)
- Heating stages
 - P.B. Hirsch and A. Howie *et al.*: *Electron microscopy of thin crystals* (1965)
- The pioneers of environmental TEM
 - First E-cells: Hashimoto *et al.* Jpn. J.
 Appl. Phys. 7, 946 (1968) (older conference paper)
 - Catalysis work: Baker and Harris
 - Carbon deposits
 - Sintering
- The differentially pumped system we know today: E.D. Boyes and P.L. Gai, Ultramicroscopy 67, 219 (1997)
 - Differential pumping built into the TEM column



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What are We Trying to Achieve?

- Obtain high-resolution information
- Dynamic responses of materials as they are exposed to reactive gases at elevated temperatures
- Surface structure of materials in various environments
- Morphology of materials in different surroundings



D. S. Su, T. Jacob, T. W. Hansen, D. Wang, R. Schlögl, B. Freitag, and S. Kujawa, *Angew. Chem.* **47**, 5005 (2008)



Methanol Synthesis

a structure-sensitive reaction



Grunwaldt et al., J. Catal. 194, 452 (2000)



Clausen et al., Topics Catal. 1, 367 (1994)

Can in situ HR-TEM unravel the details?

Equilibrium Shapes versus Gas Composition







ENVIRONMENTAL TRANSMISSION ELECTRON MICROSCOPE DESIGN



The Environmental TEM

• Methods - instrumentation





Column Design

- Monochromated FEG electron source
- Differential pumping system
 - 1. Gas is leaked in (<10Nml/min)
 - 2. First set of diffusion limiting apertures
 - 3. Turbo molecular pump
 - 4. Second set of diffusion limiting apertures
 - 5. Turbo molecular pump
 - 6. Ion getter pump (IGP)
- Flow build up pressure (<2000Pa)
- Pressure at FEG source (<10⁻⁷Pa)
- Direct line of sight!



T.W. Hansen, JBW et al., Mater. Sci. Technol. 26, 1338 (2010)





The Environmental Cell - not really a cell...





What is Environmental TEM Not?

- It is NOT UHV science
 - We have a high degree of control of the gas composition and temperature inside the sample region, BUT, it is not a UHV chamber
- It is NOT *operando* microscopy/spectroscopy
 - We are limited in especially pressure. We cannot expose samples to the conditions found in real reactors (but we are getting closer)
- It is NOT large scale science
 - It is still microscopy. We are investigating very small quantities of material
 - Kinetics and reaction products are complicated to measure

Conditions (pressure gap)

- Orders of magnitude
 - Conventional TEM ~10⁻⁸mbar
 - Environmental TEM $\sim 10^{1}$ mbar
 - Closed cell holder in TEM $\sim 10^3$ mbar
 - Bench scale reactors ~10³mbar
 - Industrial reactors ~10⁵mbar
- We have gone most of the way...









Imaging in the Fog - How does the atmosphere affect imaging



Can we get a clear view...?



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Question?



- If you have 1000Pa of gas in the sample region, how thick a sample of say, C or Ni does that correspond to?
 - Assume T = 300° C
 - C: 12u, density = 2.3×10^{6} g/m³
 - Ni: 59u, density = 8.9×10^{6} g/m³
 - Assume 10mbar in the E-cell
 - Assume pole piece gap = 5mm
 - Gas constant R=8.3 $\times\,10^{\text{-5}}\mbox{ m}^3$ bar K^{\text{-1}}\mbox{ mol}^{\text{-1}}



Solution

• Gas density:

 $pV = nRT \Rightarrow \frac{n}{V} = \frac{p}{RT}$ $\frac{n}{V} = \frac{0.01bar}{8.3 \times 10^{-5}} \frac{m^3 bar}{K \cdot mol} \times 300K = 0.4 \frac{mol}{m^3}$

• In the sample region:

$$0.4\frac{mol}{m^3} \times 0.005m = 2.0 \times 10^{-3} \frac{mol}{m^2}$$

• Ni:

$$\frac{8.9 \times 10^{6} \frac{g}{m^{3}}}{59 \frac{g}{mol}} = 1.5 \times 10^{5} \frac{mol}{m^{3}}$$

• Corresponding thickness:

$$\frac{2.0 \times 10^{-3} \frac{mol}{m^2}}{1.5 \times 10^5 \frac{mol}{m^3}} \approx 10nm$$

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Loss of Intensity

- Main effect of imaging in gas is loss of intensity
- Intensity measured on a bottom mounted camera
- Increasing pressure leads to loss of temporal resolution



T. W. Hansen and J. B. Wagner, *Microscopy and Microanalysis* 18, 684 (2012)



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T. W. Hansen and J. B. Wagner, *Microscopy and Microanalysis* 18, 684 (2012)



CTF in the Presence of Gas

 Power spectrum of amorphous carbon film (imaged at -410nm defocus)







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CTF in the Presence of Ar





Experimental Technicalities and Considerations



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Feeding gas to the E-Cell

- Due to the minute power available from conventional heating holder, even small changes in the flow rate induces major temperature changes resulting in holder and sample drift
- The total flow in the E-cell is low compared to even bench scale reactors, thus small variations in flow can result in large deviations in partial pressures of the gas components
- A high degree of control is needed to ensure accuracy and resolution in your experiment
- Digital Mass flow controllers provide accurate control of the gas flow
- Do your gases react with each other?



Cleanliness and Gases

- Due to the low total pressure (~500 Pa) and flow (~5Nml/min), online monitoring of the gas composition is crucial
 - Leaks are crucial!
 - Desorption from pipe walls from earlier experiments
- Online mass spectroscopy can be used to monitor the gas composition during your experiment
- High purity gases should be used to minimize contamination in the system
 - Your sample will see whatever impurities you have in your gas supply or from leaks in the systems (e.g. O-rings)
- For general housekeeping in the sample region, in situ plasma cleaning can be used. This can also be used to remove hydrocarbon contamination on the sample surface

- Take care! Does plasma cleaning effect your sample?

 Carrier gases are in general not used as this would significantly lower the partial pressures in the sample region and contribute to the overall contamination during the experiment

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Holders

Can provide heat to the sample

- In an ETEM:
 - Resistance to the atmosphere (e.g. oxidizing)
 - Limited power
 - Can be a problem to maintain temperature in a flowing gas
- Conventional holders are bulky and tend to drift during a heating ramp
- Alternatives
 - Laser heating
 - MEMS

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MEMS

- Micro Electro-Mechanical Systems
- Small area is heated
- Limited drift
- Fast heating and cooling ramps
- E.g. Protochips and DensSolution holder



Grids

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- Grids are usually chosen complementary to sample composition to ensure accuracy of spectroscopic data (EDX/EELS). Normally Cu grids are used (95% of sales)
- When doing *in situ* experimentation, grids must be chosen based on the conditions which the samples will be exposed to
- Things to consider:
 - Temperature. What is the melting temperature of the grid material?
 - Is the material prone to oxidation?
 - Will the grid in any way react with the gas phase in the E-cell?
- Some materials may have a significant uptake of gases
- "Use molybdenum grids for TEM studies when high temperature and inertness are needed" Quote from grid manufacturer.
 - Probably true, but not under an oxidizing atmosphere where volatile MoO_x species are formed

Cu Grids









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Stainless Steel Grids...





- Ca. 5mbar 50/50 H₂/H₂O at 750° C
- EELS shows Fe_xO_y
- ...not so stainless anymore...



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Experimental Considerations: Reference Experiments

- What do we expect to observe?
 - Assess or verify an observable effect in an external setup under the conditions in the ETEM prior to experimentation
 - Do things happen on a time scale feasible for ETEM experimentation?
- How can the effect of the beam be deconvoluted from the obtained data?
 - Verify validity of derived kinetic parameters, compare with numbers obtained from other techniques (never rely on a single technique)
 - Do ex situ investigations prior to time consuming environmental TEM studies
 - "Blind" experiments in the ETEM might elucidate a potential effect of the electron beam

Imaging Au in Hydrogen at Increasing Pressure

- Au on graphene
- P=10⁻⁶mbar
- P=2.9mbar
- P=4.3mbar





APPLICATIONS

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Solid Oxide Fuel Cells



Solid Oxide Fuel Cells



H₂O, excess fuel & oxidant gas to burner, gas turbine and heat exchanger




Fuel Cell Anode Failure





In Situ <u>Red</u>(ox) Process of Solid Oxide Fuel Cell Anode

Reduction 150Pa H_2







Q. Jeangros, JBW et al., Acta Mater. 58, 4578 (2010)

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In Situ (Red)<u>ox</u> Process of Solid Oxide Fuel Cell Anode



Oxidation 320Pa O₂





Q. Jeangros, JBW et al., Acta Mater. 58, 4578 (2010)

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Imaging at Different Length Scales -2D to 3D and irreversible changes

FIB slice of NiOx/YSZ based SOFC







Q. Jeangros, JBW et al., Acta Mater. 58, 4578 (2010)

= 250°C = 0 min

0 1/nm

SEM

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Reduction of NiO/YSZ

EFTEM imaging (O K edge), 2K/min heating ramp



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Q. Jeangros, JBW et al., Chem Commun. 50, 1808 (2014)



Reduction of NiO/YSZ







Catalyst Deactivation Mechanisms

- Catalysts are used in 90% of chemical reactions today
- $\bullet \sim \! 15\%$ of the GNP in the industrialized countries depends on catalysts
- Poisoning
 - Blockage of active sites by reactant molecules or contamination, e.g. S atoms
- Breakdown of the pellet structure
 - E.g. formation of carbonaceous filaments in steam reforming catalysts breaking the pellet structure from the inside
- Sintering
 - Growth of the active metal particles at the expense of surface area
 - One of the most important deactivation mechanisms in supported metal catalysis



Catalyst Deactivation: Ostwald Ripening



- Effectively, large particles grow on the expense of small particles
- Particle size distributions



J. A. Horsley et al., Stability of Supported Catalysts: Sintering and Redispersion (Catalytica Studies Division, 1991)





Particle Size Distribution from Ostwald-Ripening

- Theoretically, particles sintered by O-R produce a PSD with a tail on the small-diameter side and a sharp cut-off to larger diameters
- Time-independent PSD:



$$\phi_{O-R}(\tilde{d}) = \frac{81e\tilde{d}^2 \exp(1/(2\tilde{d}/3-1))}{\sqrt[3]{32}(\tilde{d}+3)^{7/3}(1.5-\tilde{d})^{11/3}}$$

R. Finsy, Langmuir 20, 2975 (2004)



Catalyst Deactivation: Particle Migration and Coalescence

Particle diffusion coefficient, Surface diffusion coefficient **Gruber formula** $D_p = 0.301 D_s \left(\frac{a}{d/2}\right)^4$ $D_s = D_0 \exp\left(\frac{-Q}{RT}\right)$ Support

G. Somorjai, Principles of Surface Chemistry (Prentice-Hall) (1976)

E. E. Gruber, J. Appl. Phys. 38, 243 (1967)

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Particle Size Distribution from Particle

- Theoretically, particles sintered by PMC produce a PSD of log-normal shape
- PSDs have a sharp cut-off on the small diameter side and a tail on the large diameter side



$$f_{L-N}(x) = y_0 + \frac{A}{\sqrt{2\pi}wx} \exp \frac{-\left[\ln \frac{x}{x_c}\right]^2}{2w^2}$$

Particle size distribution



Thanks to Nicolai Støvring and Phillip Brinck Vetter

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- Ca. 4x real time
- RT, 200Pa H₂
- Particles are more dynamic and move around the support
- Coalescence events are observed, but still occur slowly
- Resulting particles still only slowly retain an equilibrium shape









- Ca. 8x real time
- 104°C, 200Pa H₂
- Cross correlation used for image alignment
- At low temperatures, particles wobble around equilibrium positions, but do not tend to migrate long distances
- Particles in close proximity can coalesce into to single particles, but do not readily form single crystalline structures







- Ca. 8x real time
- 305°C, 200Pa H₂
- Particles still coalesce readily
- Both initial and final particles appear crystalline at all times.
- Smaller particles are absorbed by larger particles





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- Ca. 8x real time
- 403°C, 200Pa H₂
- Event following both mechanisms occur simultaneously
 - Top: PMC
 - Middle: OR





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Conclusions

- Nanoparticles are highly mobile in harsh environments
- Multiple sintering mechanisms can work simultaneously
- Mechanisms?
 - Migration and coalescence
 - Ostwald ripening
 - Suction of matter when particles are in close proximity
- Nanoparticles can merge as crystalline entities
- Mass is rapidly distributed throughout resulting particles

Copper oxide nanowires **ANISOTROPIC OXIDATION**



Copper Oxide Nanowires

• Advanced pro DTU - Gas sensors Cu Grids – Bio sensors - Field effect t • Cu grid treated in O2 at 500° C - Optoelectror DTU Cen, Technical University of Denmi um 50nm





...but how do they grow?

S. Rackauskas, JBW et al., Nano Letters 14, 5810 (2014)

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Ex situ Cu oxidation

•400°C



Ambient air

20 Pa O₂



Oxidation of Cu particles in the SEM

- Temperature: 450°C
- Atmosphere: Oxygen
- Video: 100 x realtime



M. M. Kone, M. Ahmed, and A. Fuller.



Oxidation of Copper

- Cu particle (5µm)
- 310Pa O₂
- Heating to 350°C





Oxidation of Copper

- Cu particle (5µm)
- 680Pa O₂
- Heating to 350°C





Lowmag movie of growth

- T=370°C
- P=680Pa





Nanowire length nm



Graphene(?) PLANAR GROWTH OF CARBON LAYERS

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In situ Carbon Growth on Ni

- T=650°C in 120Pa H₂
- Leaking in 3×10^{-2} Pa C₂H₂
- 0.61s between each image

→Quick initial growth shortly after flowing acetylene

→Growth of the layers and the growth front can be followed



In situ Carbon Growth on Ni





ETEM experiment; T=650°C; 120Pa $H_2/3 \times 10^{-2}$ Pa C_2H_2 \rightarrow Well aligned carbon layers at the Ni surface (a-c) \rightarrow EELS shows C edge for graphitic structure (d) \rightarrow Several growth fronts observed (e-h)

J. Kling, T. W. Hansen, JBW, Carbon 99, 261 (2016)



Soot oxidation by Ag **WATCHING THE REACTION**

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Soot oxidation by Ag catalyst

- Remove soot particles in exhaust of diesel engines by filters for a cleaner and healthier environment
- Low temperature regeneration of filters to reduce fuel consumption



DTU Cen, Technical University of Denmark D. Gardini, JBW et al. Appl. Catal. B 183, 28 (2016)



Silver Catalyst for Low Temperature Soot Oxidation

- Soot:silver= 1:5 wt:wt,
- Heating ramp = 11° C/min,
- 1 NL/min, 10.2 vol% O_2 in N_2 .



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Loose contact

• P=300 Pa O₂



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Tight contact

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• P=300 Pa O₂





Silver mobility on loose contact

- P=300 Pa O₂
- Ag/soot interface increases during oxidation



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Silver mobility on loose contact

- Ag/soot interface increases during oxidation
- Ag detaches



DTU Cen, Technical University of Denmark D. Gardini, JBW et al. Appl. Catal. B 183, 28 (2016)

Prospects for Photocatalysis studies SHINING LIGHT ON THE ETEM



Putting Light in the Microscope



In situ Cu₂O photocorrosion



- Cu_2O is a photocatalyst for water splitting under visible light illumination.
- It undergoes photodegradation in an aqueous environment.
- The L_{2.3} thresholds («white-lines») reflect the oxydation state of Cu
- The reaction is performed in absence of the electron beam
- 300 Pa H₂O with λ =405nm



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Cu₂O photocatalyst for Water splitting

- Cu₂O nanocubes are stable in the electron beam at 300 kV in high vacuum
- Reduction from Cuprous Oxide (Cu₂O) to metallic Cu in presence of water vapor

Vaultian law alastua

Degradation of Cu_2O nanocubes in H_2O (5 mbar) under visible light illumination (405 nm) for 3 hours.



• \		INT AU AIMPLEAN							4
- (-	English	Cas	Pressure	Electron been	Light intensity	Duration	Observed	
Ľ		Experiment	Gas	(mbar)	Electron beam	and wavelength	Duration	changes	100 nm
• \		1	H ₂ O vapor	3	Absent	Absent	5 h	None	-
•	۲	2	Vacuum	10^{-6}	Absent	$\lambda = 405 \text{ nm}, 6 \text{ W cm}^{-2}$	5 h	None	1.000
e		3	Vacuum	10^{-6}	$\sim 100 \ \mathrm{MW} \ \mathrm{cm}^{-2}$	Absent	20 min	None	····
	L								

- EELS spectra of Cu₂O and metallic Cu
- The $L_{2,3}$ white-lines ratio reflect the chemical state of Cu



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Controlled Atmosphere Transmission Electron Microscopy

Principles and Practice

